

<b>Notice of References Cited</b>	Application/Control No. 10/725,029	Applicant(s)/Patent Under Reexamination MEIER ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-4,704,075	11-1987	Johnston et al.	417/407
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**NON-PATENT DOCUMENTS**

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